

Patent claims

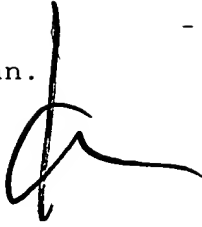
1. A method of reducing a number of measured variables of a technical system,
- 5 a) in which the measured values are divided into classes in accordance with predefined criteria;
- b) in which the measured values in a class are assessed and measured values whose assessment lies below a predefined first threshold value
- 10 are screened out;
- c) in which the classes are assessed and a class for which the assessment lies below a predefined second threshold value is screened out.
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2. The method as claimed in one of the preceding claims, in which one criterion for the division into classes consists in that, for each class, measured values relating to a predefinition of
- 20 setting parameters of the technical system are determined.
3. The method as claimed in one of the preceding claims, in which, in one class, measured values relating to a transient process and/or erroneous measured values are determined and screened out.
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4. The method as claimed in one of the preceding claims, in which, in a class, the number of measured values is reduced in that at least one representative value for the measured values in the class is determined.
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5. The method as claimed in claim 4, in which the representative value is determined as
- 35 a) an average of the measured values in the class, or
- b) a maximum value or a minimum value of the measured values in the class;

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c) a median.

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6. The method as claimed in one of the preceding claims, in which a class which has fewer than a predefined number of measured values is screened out.
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7. The method as claimed in one of the preceding claims, in which, in a class, those measured values which differ from a predefinable value by more than a predefinable threshold value are screened out.
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8. The method as claimed in one of the preceding claims, in which the reduced measured values are used for the simulation and/or for the draft design of the technical system.
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9. An arrangement for reducing a number of measured values of a technical system, having a processor unit which is set up in such a way that
- 25
- a) the measured values are divided into classes in accordance with predefined criteria;
- b) measured values in a class can be assessed and measured values whose assessment lies below a predefined first threshold value are screened out;
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- c) the classes are assessed and a class for which the assessment lies below a predefined second threshold value is screened out.
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10. The arrangement as claimed in claim 9, in which the processor unit is set up in such a way that the classes are assessed and a class for which the assessment lies below a predefined second threshold value is screened out.

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